

## AFM Probe Specifications:

Coating

Reflective Aluminum

Additional Info

AFM probes of the 200AC series are designed for tapping mode AFM imaging of standard and soft samples.

The tetrahedral AFM tip is located precisely at the free end of the AFM cantilever. This allows the AFM tip to be positioned accurately over the area of interest on the sample surface.

The uncoated AFM tip offers a sharp AFM tip apex and chemical inertness. The back side aluminum coating significantly enhances the AFM cantilever reflectivity in air and vacuum.

## AFM Tip:

Shape	Height	Setback	Radius	Half Cone Angle
Optimized Positioning	14 $\mu\text{m}$ (12 - 16 $\mu\text{m}$ )*	0 $\mu\text{m}$	< 7 nm	0° front, 35° back, <9° side

\* typical values

## AFM Cantilever:

Cantilever	Shape	Force Const.	Res. Freq.	Length	Width	Thickness
<b>Standard tapping mode AFM cantilever</b>	Beam	9 N/m (3 - 22 N/m)*	135 kHz (85 - 175 kHz)*	200 $\mu\text{m}$ (1 - 210 $\mu\text{m}$ )*	40 $\mu\text{m}$ (38 - 42 $\mu\text{m}$ )*	3.5 $\mu\text{m}$ (3 - 4 $\mu\text{m}$ )*

\* typical values